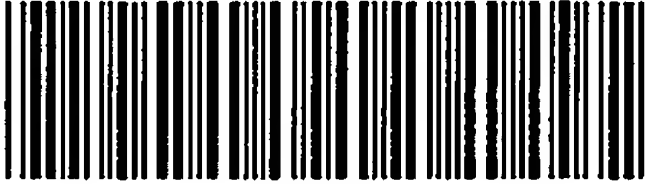


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/626,369	CHENG ET AL.	
	Examiner	Art Unit	
	Anthony Weier	1761	

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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor Search	6/9/2005	AW